


Search Notes 	Application No.	Applicant(s)	
	09/615,097	WEYER ET AL.	
	Examiner	Art Unit	
	Len Tran	1725	

SEARCHED			
Class	Subclass	Date	Examiner
164	441, 442	10/22/2003	LT
	444, 413,		
	454		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
164	Same above	10/22/2003	LT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EASt and Palm for double Patenting	10/22/2003	LT